

Tentative

CM200RL-24NF

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HIGH POWER SWITCHING USE

Notice : This is not a final specification. Some parametric limits are subject to change.

CM200RL-24NF	
● I_c	200A
● V_{CES}	1200V
●Insulated Type	
●7-elements in a pack	

APPLICATION

AC drive inverters & Servo controls, etc

ABSOLUTE MAXIMUM RATINGS ($T_j = 25\text{ }^\circ\text{C}$)

Inverter part

Symbol	Item	Conditions	Ratings	Units
V_{CES}	Collector-emitter voltage	G-E Short	1200	V
V_{GES}	Gate-emitter voltage	C-E Short	± 20	
I_c	Collector current	DC, $T_c = 72^\circ\text{C}^*1$	200	A
I_{CM}		Pulse ②	400	
I_E ①	Emitter current		200	
I_{EM} ①		Pulse ②	400	
P_c ③	Maximum collector dissipation	$T_c = 25^\circ\text{C}$	1160	W

Brake part

Symbol	Item	Conditions	Ratings	Units
V_{CES}	Collector-emitter voltage	G-E Short	1200	V
V_{GES}	Gate-emitter voltage	C-E Short	± 20	
I_c	Collector current	DC, $T_c = 80^\circ\text{C}^*1$	100	A
I_{CM}		Pulse ②	200	
P_c ③	Maximum collector dissipation	$T_c = 25^\circ\text{C}$	620	W
V_{RRM}	Repetitive peak reverse voltage	Clamp diode part	1200	V
I_{FM}	Forward current	Clamp diode part	100	A

(Common rating)

Symbol	Item	Conditions	Ratings	Units
T_j	Junction temperature		$-40 \sim +150$	$^\circ\text{C}$
T_{stg}	Storage temperature		$-40 \sim +125$	
Viso	Isolation voltage	Main terminal to base plate, AC 1 min.	2500	V
—	Torque strength	Main terminal M5	2.5~3.5	N·m
—	Torque strength	Mounting holes M5	2.5~3.5	
—	Weight	Typical value	750	g

ELECTRICAL CHARACTERISTICS ($T_j = 25\text{ }^\circ\text{C}$)

Inverter part

Symbol	Item	Conditions	Min.	Typ.	Max.	Units		
I_{CES}	Collector cutoff current	$V_{CE}=V_{CES}, V_{GE}=0V$	—	—	1	mA		
$V_{GE(th)}$	Gate-emitter threshold voltage	$I_C=20mA, V_{CE}=10V$	6	7	8	V		
I_{GES}	Gate leakage current	$V_{GE}=V_{GES}, V_{CE}=0V$	—	—	0.5	μA		
$V_{CE(sat)}$	Collector to emitter saturation voltage	$I_C=200A$ $V_{GE}=15V$	$T_j=25^\circ C$	—	2.1	3.0	V	C
			$T_j=125^\circ C$	—	2.4	—		
C_{ies}	Input capacitance	$V_{CE}=10V$ $V_{GE}=0V$	—	—	35	nF		
C_{oes}	Output capacitance		—	—	3			
C_{res}	Reverse transfer capacitance		—	—	0.68			
Q_G	Total gate charge	$V_{CC}=600V, I_C=200A, V_{GE}=15V$	—	1000	—	nC	A	
$t_{d(on)}$	Turn-on delay time	$V_{CC}=600V, I_C=200A$ $V_{GE1}=V_{GE2}=15V$ $R_G=1.6\Omega$, Inductive load switching operation	—	—	130	ns	A	
t_r	Turn-on rise time		—	—	70			
$t_{d(off)}$	Turn-off delay time		—	—	400			
t_f	Turn-off fall time		—	—	350			
t_{rr} ①	Reverse recovery time		$I_E=200A$	—	—			150
Q_{rr} ①	Reverse recovery charge		—	9	—	μC	A	
V_{EC} ①	Emitter-collector voltage	$I_E=200A, V_{GE}=0V$	—	—	3.8	V		
$R_{th(j-c)Q}$	Thermal resistance	IGBT part (1/6 module) *1	—	—	0.11	$^\circ C/W$	B	
$R_{th(j-c)R}$	Thermal resistance	FWDi part (1/6 module) *1	—	—	0.17			
$R_{th(c-f)}$	Contact thermal resistance	Case to fin, Thermal compound Applied (1/6 module) *2	—	0.051	—			
R_G	External gate resistance		1.6	—	21	Ω		

Brake Part

Symbol	Item	Conditions	Min.	Typ.	Max.	Units	
I_{CES}	Collector cutoff current	$V_{CE}=V_{CES}, V_{GE}= 0V$	—	—	1	mA	
$V_{GE(th)}$	Gate-emitter threshold voltage	$I_C= 10mA, V_{CE}= 10V$	6	7	8	V	
I_{GES}	Gate leakage current	$V_{GE}=V_{GES}, V_{CE}= 0V$	—	—	0.5	μA	
$V_{CE(sat)}$	Collector to emitter saturation voltage	$I_C = 100A$ $V_{GE}= 15V$	$T_j= 25^\circ C$	—	2.1	3.0	V
			$T_j= 125^\circ C$	—	2.4	—	
C_{ies}	Input capacitance	$V_{CE}= 10V$ $V_{GE}= 0V$	—	—	17.5	nF	
C_{oes}	Output capacitance		—	—	1.5		
C_{res}	Reverse transfer capacitance		—	—	0.34		
Q_G	Total gate charge	$V_{CC}= 600V, I_C= 100A, V_{GE}=15V$	—	500	—	nC	
V_{FM}	Forward voltage drop	$I_F= 100A$	—	—	3.8	V	
$R_{th(j-c)Q}$	Thermal resistance	IGBT part ^{*1}	—	—	0.20	$^\circ C/W$	
$R_{th(j-c)R}$		Clamp diode part ^{*1}	—	—	0.28		

*1: T_c measured point is just under the chips.

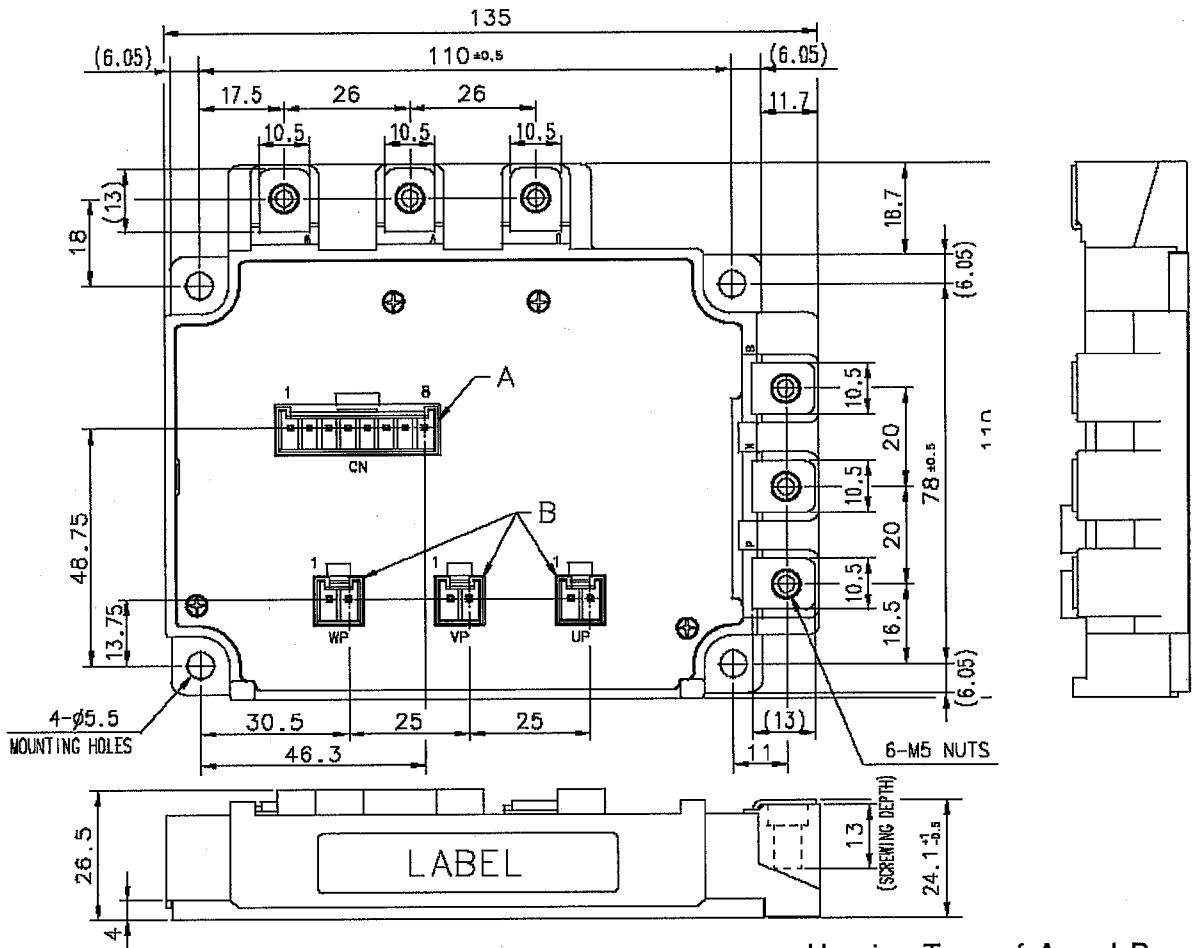
If you use this value, $R_{th(f-a)}$ should be measured just under the chips.

*2: Typical value is measured by using Shin-etsu Silicone "G-746".

- ① $I_E, V_{EC}, t_{rr}, Q_{rr}$ represent characteristics of the anti-parallel, emitter to collector free-wheel diode (FWDi).
- ② Pulse width and repetition rate should be such that the device junction temp. (T_j) dose not exceed T_{jmax} rating.
- ③ Junction temperature (T_j) should not increase beyond $150^\circ C$.
- ④ Pulse width and repetition rate should be such as to cause neglible temperature rise.

OUTLINE DRAWING

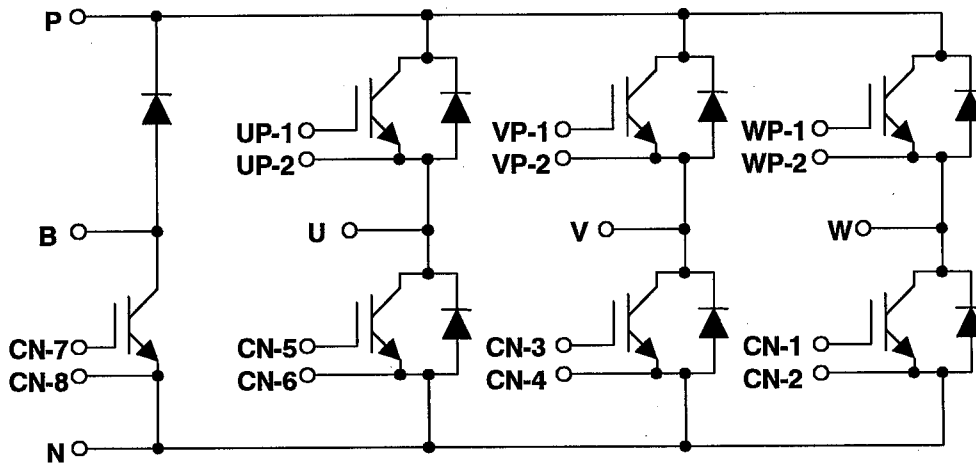
Dimensions in mm



A

Housing Type of A and B
 (J.S.T.Mfg.Co.Ltd)
 A= B8P-VH-FB-B, B= B2P-VH-FB-B

CIRCUIT DIAGRAM



CHIP LAYOUT DRAWING

Dimensions in mm

A	B
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